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Application/Control No.	Applicant(s)/Patent under Reexamination	•
10/626,432	TOJO ET AL.	
Examiner	Art Unit	
Eva Yi Zheng	2611	

	SEARCHED		
Class	Subclass	Date	Examiner
375	146	7/15/2007	E.Z
375	346	7/15/2007	E.Z
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
updated EAST search	7/15/2007	E.Z
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